

RELIABILITY MONITOR

PROCESS: 2P, 2M, 0.6um, P2Cap, PdD, HP Vts, GOI, WJ BPSG, N+ESDII,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS21352	A4	JUN '01	27346	0103	ATP (Amkor, PI)	DN033071AAA	LQFP	336	77	0
DS21352	A4	JUN '01	27346	0103	ATP (Amkor, PI)	DN033071AAA	LQFP	1000	77	0

TOTALS: FAIL RATE (Fits): 13 DEVICE HRS: 7.14E+07 0

RELIABILITY MONITOR

PROCESS: 2P, 2M, 0.8um, Nd Cap, P2 Cap , N+ESDII, Ti/TiN , WJ BPSG,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2154	A2	SEP '01	27841	0125	ATK (Amkor, K)	DN104641AA-	LQFP	336	80	0
DS2154	A2	SEP '01	27841	0125	ATK (Amkor, K)	DN104641AA-	LQFP	1000	80	0
DS2154	A2	DEC '01	28583	0126	ATP (Amkor, PI)	DK119150AAA	LQFP	336	80	0
DS2154	A2	JUN '01	27101	0107	Stats	DC040702AA-	LQFP	336	77	0
DS2154	A2	JUN '01	27101	0107	Stats	DC040702AA-	LQFP	1000	76	0

TOTALS:

FAIL RATE (Fits): 5 DEVICE HRS: 1.72E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdplDiode , WJ BPSG, N+ESD II,

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	FEB '01	26609	0105	OSEP	DE047362AAB	SOIC	48	232	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	MAY '01	26993	0115	Carsem	DM052456AC	SOIC	336	77	0
DS1803	A2	MAY '01	26993	0115	Carsem	DM052456AC	SOIC	1000	76	0
DS1803	A2	AUG '01	27563	0119	OSEP	DE105519ACA	SOIC	1000	80	0

TOTALS:

FAIL RATE (Fits): 7 DEVICE HRS: 1.29E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.6um,SiIP1,NdA,PD,Ti/TiN M1+M2,WJ BPSG,N+ESD,CtE,

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS80CH11	A4	MAR '01	27058	0103	ATK (Amkor, K)	DN029182AAA	LQFP	48	235	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS80CH11	A4	JUN '01	27107	0108	ATK (Amkor, K)	DN034351AA	LQFP	336	77	2
DS80CH11	A4	MAR '01	26786	0103	ATK (Amkor, K)	DN029182AAA	LQFP	336	77	0
DS80CH11	A4	MAR '01	26786	0103	ATK (Amkor, K)	DN029182AAA	LQFP	1000	73	0
DS80CH11	A4	SEP '01	27867	0110	Stats	DC037148AA	LQFP	336	80	0

TOTALS:

FAIL RATE (Fits): 24 DEVICE HRS: 1.29E+08 2

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdpIDiode, Ti/TiN M1+M2 , WJ BPSG, N+ESD II,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	FEB '01	26610	0105	OSEP	DE047362AAB	SOIC	336	77	0
DS1803	A2	AUG '01	27563	0119	OSEP	DE105519ACA	SOIC	336	80	0
DS1803	A2	FEB '01	26610	0105	OSEP	DE047362AAB	SOIC	1000	77	0

TOTALS:

FAIL RATE (Fits): 9 DEVICE HRS: 9.73E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.6um, Pd, Ti/TiN M1 , WJ BPSG ,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2401	C2	SEP '01	27884	0130	Fastech	DA033008AJ	TO92	336	80	0
DS2401	C2	SEP '01	27884	0130	Fastech	DA033008AJ	TO92	1000	80	0

TOTALS: FAIL RATE (Fits): 12 DEVICE HRS: 7.55E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M,0.6um,BCs,SiIP1,Nd,PdD,Ti/TiN M1, WJ BPSG, N+ESDII,

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS5002	C5	JAN '01	26508	0047	ATK (Amkor, K)	DN028766AAD	MQFP	48	198	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS5002	C5	JAN '01	26509	0047	ATK (Amkor, K)	DN028766AAD	MQFP	336	77	0
DS5002	C5	APR '01	26901	0112	ATK (Amkor, K)	DN030363AAA	MQFP	336	77	0
DS5002	C6	JUL '01	27364	0122	ATK (Amkor, K)	DN042297AAA	MQFP	336	80	0
DS5002	C6	JUL '01	27364	0122	ATK (Amkor, K)	DN042297AAA	MQFP	1000	80	0
DS5002	C5	APR '01	26901	0112	ATK (Amkor, K)	DN030363AAA	MQFP	1000	77	0
DS5002	C5	JAN '01	26509	0047	ATK (Amkor, K)	DN028766AAD	MQFP	1000	77	0

TOTALS:

FAIL RATE (Fits): 4 DEVICE HRS: 2.28E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.6um, SiIP1, Pd, Ti/TiN M1 , N+ESDII,BPSG ILO,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS80C320	C5	APR '01	26894	0111	CPS (ChipPac, China)	DH040746AA	PDIP	336	77	0
DS80C320	C5	APR '01	26894	0111	CPS (ChipPac, China)	DH040746AA	PDIP	1000	77	0

TOTALS: FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.6um,ALOCOS,NZTC P1R,PdpID,Low Vts,BPSG, N+ESDII,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2118M	B1	SEP '01	27874	0124	Carsem	DM106644AA	SSOP	336	80	0
DS2118M	B1	SEP '01	27874	0124	Carsem	DM106644AA	SSOP	1000	70	0

TOTALS:

FAIL RATE (Fits): 14 DEVICE HRS: 6.60E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.6um, Pdepletion, Low Vts , WJ BPSG ,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	DATE	JOB NO	DATE	ASSEMBLY	LOT NO.	PACKAGE	READ	POINT	QTY	FAILS
DS21Q43	A3-A	SEP '01	27880	0047	Stats	DC036714AAD	LQFP	336	70	0	

TOTALS: FAIL RATE (Fits): 41 DEVICE HRS: 2.22E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.8um, PdpIDiode, Low Vts , N+ESDII, WJ BPSG,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232	C2-L	JUL '01	27339	0105	ATP (Amkor, PI)	DK046225AB	SOIC	336	80	0
DS1232	C2-L	JUL '01	27339	0105	ATP (Amkor, PI)	DK046225AB	SOIC	1000	80	0
DS1232	C2-L	APR '01	26864	0105	OSEP	DE045054ABB	SOIC	336	77	0
DS1232	C2-L	APR '01	26864	0105	OSEP	DE045054ABB	SOIC	1000	77	0

TOTALS:

FAIL RATE (Fits): 6 DEVICE HRS: 1.48E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.8um,Neg ZTC P1R,PdpID,Low Vts,BPSG ILO, N+ESDII,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS21S07	C1-	FEB '01	26588	0047	Carsem	DM035532AF	TSSOP	336	77	0
DS21S07	C1-	FEB '01	26588	0047	Carsem	DM035532AF	TSSOP	1000	77	0

TOTALS:

FAIL RATE (Fits): 14 DEVICE HRS: 6.76E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.8um, E2PROM, DSD w/LV Wells ,HVPchVtII,WJ BPSG,

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1620	D1	MAR '01	26776	0106	CPS (ChipPac, China)	DH045040AA	SOIC	48	237	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1620	D1	DEC '01	28593	0112	CPS (ChipPac, China)	DH052443AAD	SOIC	336	80	0
DS1620	D1	JUN '01	27093	0109	CPS (ChipPac, China)	DH046190AAI	SOIC	336	77	0
DS1620	D1	JUN '01	27093	0109	CPS (ChipPac, China)	DH046190AAI	SOIC	1000	77	0
DS1620	D1	SEP '01	27859	0111	NSEB	DJ051232AAI	SOIC	336	80	0
DS1620	D1	SEP '01	27859	0111	NSEB	DJ051232AAI	SOIC	1000	80	0

TOTALS: FAIL RATE (Fits): 5 DEVICE HRS: 1.73E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 1.2um, II Poly1 , TEOS Spacer,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1267	A1	MAY '01	26979	0104	ATP (Amkor, PI)	DK043419AAB	TSSOP	336	75	0
DS1267	A1	MAY '01	26979	0104	ATP (Amkor, PI)	DK043419AAB	TSSOP	1000	75	0

TOTALS: FAIL RATE (Fits): 13 DEVICE HRS: 6.95E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 1.2um, ZTC P1, Ndepletion ,Latell ZTC,TEOSsp,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1233	A5	JUL '01	27352	0110	Carsem	DM048543AA	SOT223	336	68	0
DS1233	A5	APR '01	26871	0101	Fastech	DA048537AF	SOT223	336	77	0
DS1233	A5	OCT '01	28006	0128	Fastech	DA102602AC	SOT223	336	68	0
DS1233	A5	APR '01	26871	0101	Fastech	DA048537AF	SOT223	1000	77	0

TOTALS:

FAIL RATE (Fits): 8 DEVICE HRS: 1.16E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 2.0um, Pfield , WJ BPSG ,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175	D1	APR '01	26883	0050	ATP (Amkor, PI)	DK036683AB	SOIC	336	77	0
DS2175	D1	APR '01	26883	0050	ATP (Amkor, PI)	DK036683AB	SOIC	1000	77	0

TOTALS: FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0

RELIABILITY MONITOR

PROCESS: 1P,1M,5.0um,NegZTC P1R,30VNF&PF,UVNd&Pd,N+ESD,TEOS,SchotP-,

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B7	AUG '00	25857	0029	ATP (Amkor, PI)	DK016058AA	SOIC	48	231	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B7	AUG '00	25858	0029	ATP (Amkor, PI)	DK016058AA	SOIC	336	77	0
DS2108	B7	AUG '00	25858	0029	ATP (Amkor, PI)	DK016058AA	SOIC	1000	76	0

TOTALS:

FAIL RATE (Fits): 11 DEVICE HRS: 8.13E+07 0